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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10083481	02/27/2002	250		2881	

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**\*\*CONTINUING DATA VERIFIED:**

THIS APPLICATION IS A CON OF 09/883,184 06/19/2001  
WHICH IS A CON OF 09/131,383 08/07/1998 PAT 6,348,690

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**\*\* FOREIGN APPLICATIONS VERIFIED:**

JAPAN 9-212908 03/07/1997

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		29273/559
Verified and Acknowledged Examiners's Initials		
TITLE : Method and an apparatus of an inspection system using an electron beam		
U.S. DEPT. OF COMM./PAT. & TM-PTO-435L (Rev. 12-94)		

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G
Assistant Examiner		DRAWING	
ISSUE FEE		Sheets Drwg.	Figs. Drwg.
Amount Due	Date Paid	Print Fig.	
Primary Examiner		Application Examiner	
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	
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